

<b>Search Notes</b> 	<b>Application/Contr. I No.</b> 10/795,770	<b>Applicant(s)/Patent under Reexamination</b> HATAKEYAMA ET AL.
	<b>Examiner</b> Tamai I.E. Karl	<b>Art Unit</b> 2834

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See attached		5/30/06	SM